

# **PMV213SN**

 $\mu Trench MOS^{\intercal_M}$  standard level FET

Rev. 02 — 19 February 2003

**Product data** 

## 1. Product profile

### 1.1 Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS $^{\text{TM}}$  technology.

Product availability:

PMV213SN in SOT23.

#### 1.2 Features

Low on-state resistance in a small surface mount package.

### 1.3 Applications

DC-to-DC primary side switching.

#### 1.4 Quick reference data

- $V_{DS}$  ≤ 100 V
- Arr  $P_{tot} \le 2 W$

- I<sub>D</sub> ≤ 1.9 A
- Arr R<sub>DSon</sub>  $\leq$  250 m $\Omega$

## 2. Pinning information

Table 1: Pinning - SOT23 simplified outline and symbol

	3				
Pin	Description	Simplified outline		Symbol	
1	gate (g)				
2	source (s)			d	
3	drain (d)		12	g MBB076 S	
			Top view MSB003		
			SOT23		





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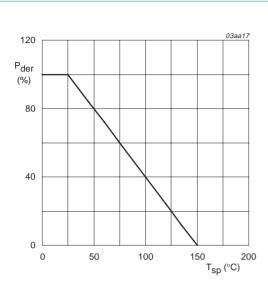
## 3. Limiting values

#### Table 2: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

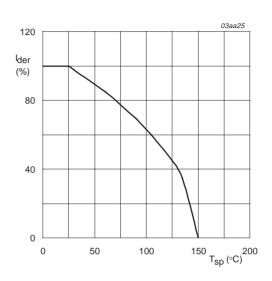
Symbol	Parameter	Conditions	Min	Max	Unit	
$V_{DS}$	drain-source voltage (DC)	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	100	V	
$V_{DGR}$	drain-gate voltage (DC)	$25~^{\circ}\text{C} \le \text{T}_{\text{j}} \le 150~^{\circ}\text{C}; \text{R}_{\text{GS}} = 20~\text{k}\Omega$	-	100	V	
$V_{GS}$	gate-source voltage (DC)		-	±30	V	
I <sub>D</sub>	drain current (DC)	$T_{sp}$ = 25 °C; $V_{GS}$ = 10 V; Figure 2 and 3	-	1.9	Α	
		T <sub>sp</sub> = 100 °C; V <sub>GS</sub> = 10 V; Figure 2	-	1.2	А	
I <sub>DM</sub>	peak drain current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; Figure 3	-	7.6	Α	
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; Figure 1	-	2	W	
T <sub>stg</sub>	storage temperature		<b>–</b> 55	+150	°C	
T <sub>j</sub>	junction temperature		<b>–</b> 55	+150	°C	
Source-drain diode						
I <sub>S</sub>	source (diode forward) current (DC)	T <sub>sp</sub> = 25 °C	-	1.7	Α	
I <sub>SM</sub>	peak source (diode forward) current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$	-	6.9	Α	

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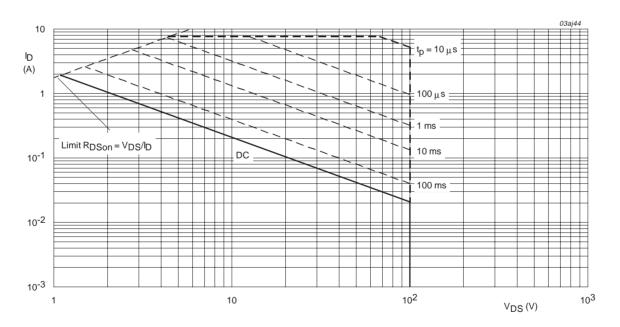
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature.



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature.



 $T_{sp}$  = 25 °C;  $I_{DM}$  is single pulse;  $V_{GS}$  = 10V

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

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### 4. Thermal characteristics

#### **Table 3: Thermal characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point	Figure 4	-	-	60	K/W

## 4.1 Transient thermal impedance

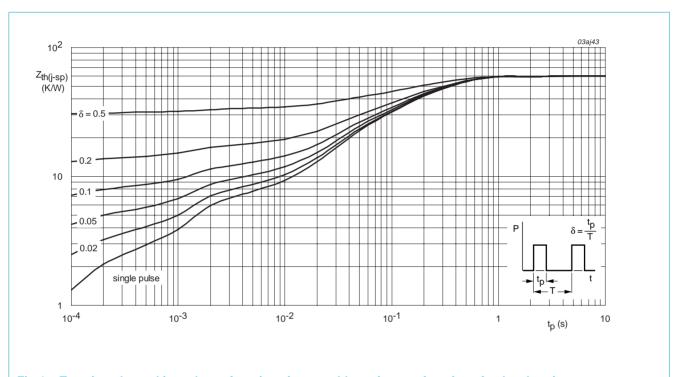


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration.

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## 5. Characteristics

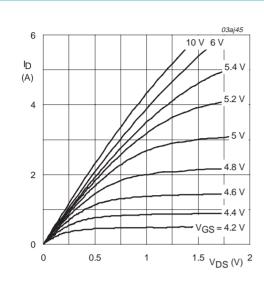
Table 4: Characteristics

 $T_i = 25 \,^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_D = 250 \mu\text{A};  V_{GS} = 0  \text{V}$				
		T <sub>j</sub> = 25 °C	100	-	-	V
		T <sub>j</sub> = −55 °C	90	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; \text{ Figure 9}$				
		T <sub>j</sub> = 25 °C	2	3	4	V
		T <sub>j</sub> = 150 °C	1.2	-	-	V
		T <sub>j</sub> = −55 °C	-	-	4.4	V
I <sub>DSS</sub>	drain-source leakage current	V <sub>DS</sub> = 100 V; V <sub>GS</sub> = 0 V				
		T <sub>j</sub> = 25 °C	-	-	1	μΑ
		T <sub>j</sub> = 150 °C	-	-	100	μΑ
$I_{GSS}$	gate-source leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nΑ
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 0.5 A; Figure 7 and 8				
		T <sub>j</sub> = 25 °C	-	213	250	$m\Omega$
		T <sub>j</sub> = 150 °C	-	490	575	$m\Omega$
Dynamic	characteristics					
Q <sub>g(tot)</sub>	total gate charge	$I_D = 1.2 \text{ A}; V_{DD} = 80 \text{ V}; V_{GS} = 10 \text{ V}; Figure 13$		7	-	nC
Q <sub>gs</sub>	gate-source charge		-	1.4	-	nC
$Q_{gd}$	gate-drain (Miller) charge		-	2.5	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 20 \text{ V}; f = 1 \text{ MHz}; Figure 11$		330	-	pF
C <sub>oss</sub>	output capacitance		-	36	-	рF
C <sub>rss</sub>	reverse transfer capacitance		-	22	-	рF
t <sub>d(on)</sub>	turn-on delay time	$V_{DD}$ = 50 V; $R_L$ = 33 $\Omega$ ; $V_{GS}$ = 10 V; $R_G$ = 6 $\Omega$	-	5.5	-	ns
t <sub>r</sub>	rise time		-	5	-	ns
t <sub>d(off)</sub>	turn-off delay time			9.5	-	ns
t <sub>f</sub>	fall time		-	3	-	ns
Source-	Irain diode					
$V_{SD}$	source-drain (diode forward) voltage	I <sub>S</sub> = 1.5 A; V <sub>GS</sub> = 0 V; Figure 12	-	0.83	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 1.2 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V}$	-	36	-	ns
Q <sub>r</sub>	recovered charge		-	23	-	nC

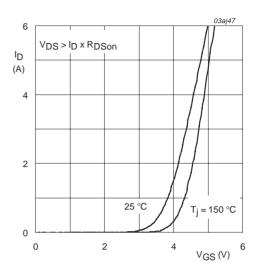
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T<sub>i</sub> = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



 $T_j$  = 25 °C and 150 °C;  $V_{DS} > I_D \times R_{DSon}$ 

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

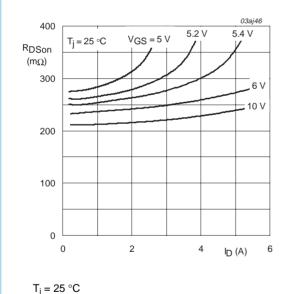
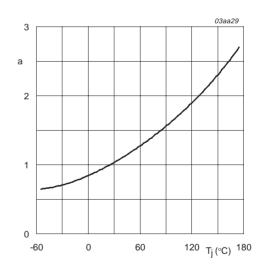


Fig 7. Drain-source on-state resistance as a function

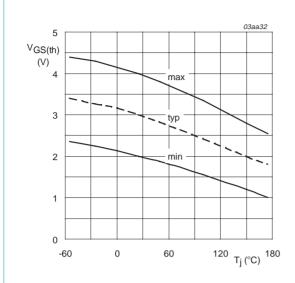
of drain current; typical values.



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

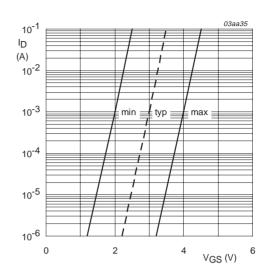
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature.

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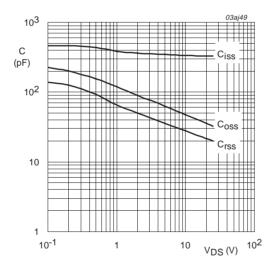
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature.



T<sub>i</sub> = 25 °C

Fig 10. Sub-threshold drain current as a function of gate-source voltage.

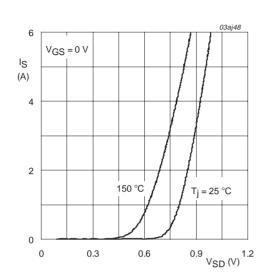


 $V_{GS} = 0 V$ ; f = 1 MHz

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

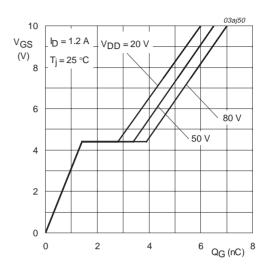
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 $T_i$  = 25 °C and 150 °C;  $V_{GS}$  = 0 V

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.



 $I_D = 1.2 \text{ A}$ ;  $V_{DD} = 20 \text{ V}$ , 50 V, 80 V

Fig 13. Gate-source voltage as a function of gate charge; typical values.

## 6. Package outline

Plastic surface mounted package; 3 leads

SOT23

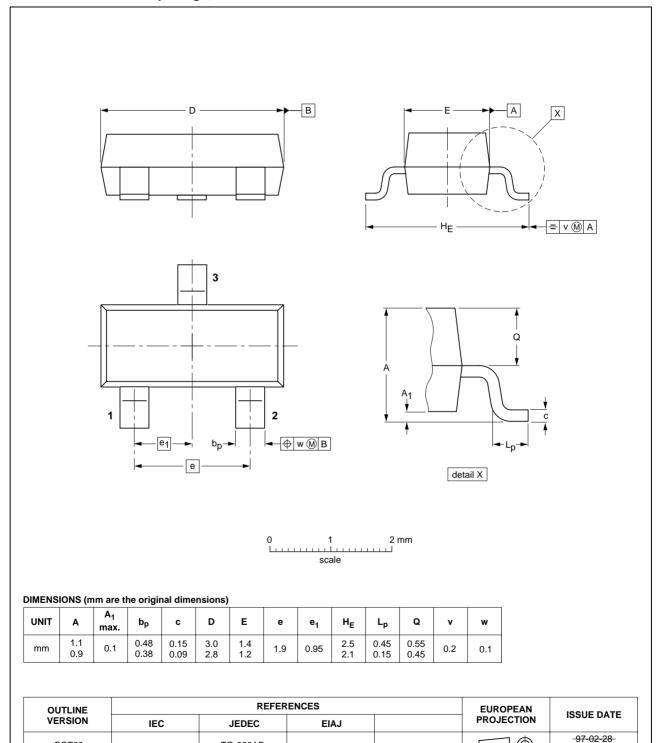


Fig 14. SOT23.

SOT23

99-09-13

 $\square$ 

TO-236AB



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## 7. Revision history

### **Table 5: Revision history**

Rev	Date	CPCN	Description
02	20030219	-	Product data (9397 750 11128)
			Modifications:
			<ul> <li>Section 1.4 "Quick reference data" I<sub>D</sub> modified due to improved R<sub>th</sub>.</li> </ul>
			<ul> <li>Section 1.4 "Quick reference data" P<sub>tot</sub> modified due to improved R<sub>th</sub>.</li> </ul>
			<ul> <li>Section 3 "Limiting values" I<sub>D</sub>, I<sub>DM</sub>, P<sub>tot</sub>, I<sub>S</sub>, I<sub>SM</sub> modified due to improved R<sub>th</sub>.</li> </ul>
			<ul> <li>Section 3 "Limiting values" Figure 3 SOA graph modified due to improved R<sub>th</sub>.</li> </ul>
			<ul> <li>Section 4 "Thermal characteristics" R<sub>th(j-sp)</sub> improved.</li> </ul>
			<ul> <li>Section 4 "Thermal characteristics" Figure 4 to reflect the improvement in R<sub>th(j-sp)</sub>.</li> </ul>
01	20030115	-	Product data (9397 750 10893)

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#### 8. Data sheet status

Level	Data sheet status <sup>[1]</sup>	Product status <sup>[2][3]</sup>	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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